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Form PTO 1449		U.S. DEPARTMEN		ATTY DOCKET NO.		SERIAL NO.	
(Modified)		PATENT AND TRA	ADEMARK OFFICE	283189US0PCT		10/563,565	
				APPLICANT			
LIST OF	REFE	RENCES CITED BY A	PPLICANT	Keisuke FUNAKI, et al.			
				FILING DATE		GROUP	
				January 6, 2006		2862	
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS		FILING DATE IF APPROPRIATE
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	AO	CN 1137970A	12/18/1996	CHINA (submitting front page with Engl Abstract only, corr. US 5,804,111)			S NO X
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ				Addi	tional Refe	erences sheet(s) attached
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							
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